

Issue Classification	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/786,539	KOMAZAWA ET AL.
Examiner	Art Unit	
Ching Chang	3748	

ISSUE CLASSIFICATION

ORIGINAL			CROSS REFERENCE(S)					
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)					
123	90.15	123	90.17					
INTERNATIONAL CLASSIFICATION		4644	160					
F	O	I	L	1	134			
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				/				
				/				

Ching Chay 07/01/05

(Assistant Examiner) (Date)

THOMAS DENION
SUPERVISORY PATENT EXAMINER
TECHNOLOGY CENTER 3700

Total Claims Allowed: 14

Allen Breuer 1/6/05
(Legal Instruments Examiner) (Date)

(Legal Instruments Examiner) (Date)

(Primary Examiner)

(Date) ✓

14

O.G.

HISTORICAL.

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant		<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47	
Final	Original	Final	Original	Final	Original	Final	Original
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6	6	36	66	96	126	156	186
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